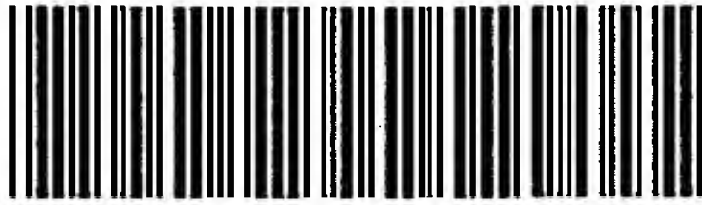


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,452	YANG ET AL.	
	Examiner	Art Unit	
	Binh X. Tran	1765	

SEARCHED			
Class	Subclass	Date	Examiner
438	745	7/19/2005	BT
438	747	7/19/2005	BT
438	754	7/19/2005	BT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUG, JPO, EPO	7/19/2005	BT